# **4 A Synchronous Buck Power MOSFET Driver**

The NCP5351 is a dual MOSFET gate driver optimized to drive the gates of both high-side and low-side Power MOSFETs in a Synchronous Buck converter. The NCP5351 is an excellent companion to multiphase controllers that do not have integrated gate drivers, such as ON Semiconductor's CS5323, CS5305 or CS5307. This architecture provides a power supply designer the flexibility to locate the gate drivers close to the MOSFETs.

The 4.0 A drive capability makes the NCP5351 ideal for minimizing switching losses in MOSFETs with large input capacitance. Optimized internal, adaptive nonoverlap circuitry further reduces switching losses by preventing simultaneous conduction of both MOSFETs.

The floating top driver design can accommodate MOSFET drain voltages as high as 25 V. Both gate outputs can be driven low, and supply current reduced to less than 25 µA, by applying a low logic level to the Enable (EN) pin. An undervoltage lockout function ensures that both driver outputs are low when the supply voltage is low, and a thermal shutdown function provides the IC with overtemperature protection.

The NCP5351 is pin-to-pin compatible with the SC1205 and is available in a standard SO-8 package and thermally enhanced DFN10.

#### **Features**

- 4.0 A Peak Drive Current
- Rise and Fall Times < 15 ns Typical into 6000 pF
- Propagation Delay from Inputs to Outputs < 20 ns
- Adaptive Nonoverlap Time Optimized for Large Power MOSFETs
- Floating Top Driver Accommodates Applications Up to 25 V
- Undervoltage Lockout to Prevent Switching when the Input Voltage is Low
- Thermal Shutdown Protection Against Overtemperature
- < 1.0 mA Quiescent Current Enabled
- 25 µA Quiescent Current Disabled
- Internal TG to DRN Pulldown Resistor Prevents HV Supply-Induced Turn On of High-Side MOSFET
- Pb-Free Package is Available



# ON Semiconductor®

http://onsemi.com

# **MARKING DIAGRAMS**



SO-8 **D SUFFIX CASE 751** 





DFN10 **MN SUFFIX** CASE 485C



= Assembly Location

= Wafer Lot

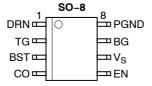
= Year

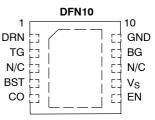
W = Work Week

= Pb-Free Package

(Note: Microdot may be in either location)

# **PIN CONNECTIONS**





#### ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 12 of this data sheet.

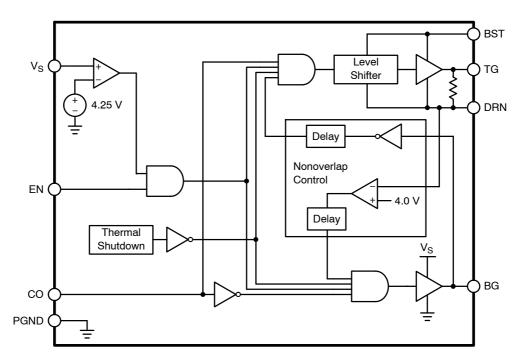


Figure 1. Block Diagram

Table 1. Input-Output Truth Table

EN	СО	DRN	TG	BG
L	Х	Х	L	L
Н	L	< 3.0 V	L	Н
Н	Н	< 3.0 V	Н	L
Н	L	> 5.0 V	L	L
Н	Н	> 5.0 V	Н	L

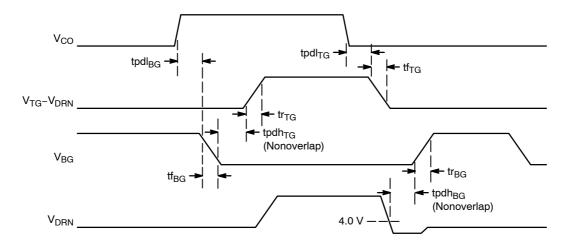


Figure 2. Timing Diagram

# PACKAGE PIN DESCRIPTION

Pin N	umber		
SO-8	SO-8 DFN-10 Pin Symbol		Description
1	1	DRN	The switching node common to the high and low-side FETs. The high-side (TG) driver and supply (BST) are referenced to this pin.
2	2	TG	Driver output to the high-side MOSFET gate.
3	4	BST	Bootstrap supply voltage input. In conjunction with a Schottky diode to $V_S$ , a 0.1 $\mu F$ to 1.0 $\mu F$ ceramic capacitor connected between BST and DRN develops supply voltage for the high–side driver (TG).
4	5	CO	Logic level control input produces complementary output states – no inversion at TG; inversion at BG.
-	3, 8	N/C	Not Connected.
5	6	EN	Logic level enable input forces TG and BG low, and supply current to 10 $\mu\text{A}$ when EN is low.
6	7	V <sub>S</sub>	Power supply input. A 0.1 $\mu\text{F}$ to 1.0 $\mu\text{F}$ ceramic capacitor should be connected from this pin to PGND.
7	9	BG	Driver output to the low-side (synchronous rectifier) MOSFET gate.
8	_	PGND	Ground.
_	10	GND	Ground.

# **MAXIMUM RATINGS - SO-8**

Rating	Value	Unit	
Operating Junction Temperature, T <sub>J</sub>		Internally Limited	°C
Package Thermal Resistance: SO-8 Junction-to-Case, $R_{\theta JC}$ Junction-to-Ambient, $R_{\theta JA}$		45 165	°C/W
Storage Temperature Range, T <sub>S</sub>		-65 to 150	°C
Lead Temperature Soldering:	Reflow: (SMD styles only) (Note 1) Pb-Free	230 peak 260 peak	°C
MSL Rating		1	-

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

NOTE: This device is ESD sensitive. Use standard ESD precautions when handling.

1. 60 seconds maximum above 183°C.

#### **MAXIMUM RATINGS - DFN-10**

Rating		Symbol	Value	Unit
Thermal Resistance, Junction-to-Air		$R_{JA}$	68.5	°C/W
Operating Ambient Temperature Range		T <sub>A</sub>	-30 to 85	°C
ESD Withstand Voltage	Human Body Model (Note 2) Machine Model (Note 2)	V <sub>ESD</sub>	> 2500 > 150	V
Moisture Sensitivity		MSL	Level 1	
Storage Temperature Range		T <sub>stg</sub>	-55 to 150	°C
Junction Operating Temperature		$T_J$	-30 to 125	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

2. This device series contains ESD protection and exceeds the following tests:

Human Body Model, 100 pF discharge through a 1.5 k $\Omega$  following specification JESD22/A114. Machine Model, 200 pF discharged through all pins following specification JESD22/A115. Latchup as per JESD78 Class II: > 100 mA.

# **MAXIMUM RATINGS**

Pin Symbol	Pin Name	V <sub>MAX</sub>	V <sub>MIN</sub>	I <sub>SOURCE</sub>	I <sub>SINK</sub>
V <sub>S</sub>	Main Supply Voltage Input	6.3 V	-0.3 V	NA	4.0 A Peak (< 100 μs) 250 mA DC
BST	Bootstrap Supply Voltage Input	25 V wrt/PGND 6.3 V wrt/DRN	-0.3 V wrt/DRN	NA	4.0 A Peak (< 100 μs) 250 mA DC
DRN	Switching Node (Bootstrap Supply Return)	25 V	-1.0 V DC -5.0 V for 100 ns -6.0 V for 20 ns	4.0 A Peak (< 100 μs) 250 mA DC	NA
TG	High-Side Driver Output (Top Gate)	25 V wrt/PGND 6.3 V wrt/DRN	-0.3 V wrt/DRN	4.0 A Peak (< 100 μs) 250 mA DC	4.0 A Peak (< 100 μs) 250 mA DC
BG	Low-Side Driver Output (Bottom Gate)	6.3 V	-0.3 V	4.0 A Peak (< 100 μs) 250 mA DC	4.0 A Peak (< 100 μs) 250 mA DC
CO	TG & BG Control Input	6.3 V	-0.3 V	1.0 mA	1.0 mA
EN	Enable Input	6.3 V	-0.3 V	1.0 mA	1.0 mA
PGND	Ground	0 V	0 V	4.0 A Peak (< 100 μs) 250 mA DC	NA

NOTE: All voltages are with respect to PGND except where noted.

 $\textbf{ELECTRICAL CHARACTERISTICS} \ (0^{\circ}\text{C} < \text{T}_{\text{J}} < 125^{\circ}\text{C}; \ V_{\text{S}} = 5.0 \ \text{V}; \ 4.0 \ \text{V} < \text{V}_{\text{BST}} < 25 \ \text{V}; \ V_{\text{EN}} = \text{V}_{\text{S}}; \ \text{unless otherwise noted})$ 

Parameter	Test Conditions	Min	Тур	Max	Unit
DC OPERATING SPECIFICATIONS POWER SUPPLY	8				
V <sub>S</sub> Quiescent Current, Operating	V <sub>CO</sub> = 0 V, 4.5 V; No output switching	_	1.0	-	mA
V <sub>BST</sub> Quiescent Current, Operating	V <sub>CO</sub> = 0 V, 4.5 V; No output switching	-	50	-	μΑ
Quiescent Current, Non-Operating	V <sub>EN</sub> = 0 V; V <sub>CO</sub> = 0 V, 4.5 V	-	-	25	μΑ
Undervoltage Lockout					
Start Threshold	CO = 0 V	4.05	4.25	4.48	V
Hysteresis	CO = 0 V	-	275	-	mV
CO INPUT CHARACTERISTICS					
High Threshold	-	2.0	-	-	V
Low Threshold	-	_	-	0.8	V
Input Bias Current	0 < V <sub>CO</sub> < V <sub>S</sub>	_	0	1.0	μΑ
EN INPUT CHARACTERISTICS					
High Threshold	Both outputs respond to CO	2.0	-	-	V
Low Threshold	Both outputs are low, independent of CO	-	-	0.8	V
Input Bias Current	0 < V <sub>EN</sub> < V <sub>S</sub>	-	0	10	μΑ
THERMAL SHUTDOWN					
Overtemperature Trip Point	-	-	170	-	°C
Hysteresis	-	-	30	-	°C
HIGH-SIDE DRIVER					
Peak Output Current	-	_	4.0	-	Α
Output Resistance (Sourcing)	Duty Cycle < 2.0%, Pulse Width < 100 $\mu$ s, T <sub>J</sub> = 125°C, V <sub>BST</sub> - V <sub>DRN</sub> = 4.5 V, V <sub>TG</sub> = 4.0 V + V <sub>DRN</sub>	-	0.5	-	Ω
Output Resistance (Sinking)	Duty Cycle < 2.0%, Pulse Width < 100 $\mu$ s, T <sub>J</sub> = 125°C, V <sub>BST</sub> - V <sub>DRN</sub> = 4.5 V, V <sub>TG</sub> = 0.5 V + V <sub>DRN</sub>	_	0.42	-	Ω
LOW-SIDE DRIVER					
Peak Output Current	-	_	4.0	-	Α
Output Resistance (Sourcing)	Duty Cycle < 2.0%, Pulse Width < 100 $\mu$ s, T <sub>J</sub> = 125°C, V <sub>S</sub> = 4.5 V, V <sub>BG</sub> = 4.0 V	_	0.6	-	Ω
Output Resistance (Sinking)	Duty Cycle < 2.0%, Pulse Width < 100 $\mu$ s, T <sub>J</sub> = 125°C, V <sub>S</sub> = 4.5 V, V <sub>BG</sub> = 0.5 V	-	0.42	-	Ω

**ELECTRICAL CHARACTERISTICS (continued)** (0°C <  $T_J$  < 125°C;  $V_S$  = 5.0 V; 4.0 V <  $V_{BST}$  < 25 V;  $V_{EN}$  =  $V_S$ ,  $C_{LOAD}$  = 5.7 nF; unless otherwise noted.)

Parameter	Test Conditions	Min	Тур	Max	Unit
AC OPERATING SPECIFICATIONS HIGH-SIDE DRIVER	3				
Rise Time	V <sub>BST</sub> – V <sub>DRN</sub> = 5.0 V, T <sub>J</sub> = 125°C	_	8.0	16	ns
Fall Time	V <sub>BST</sub> – V <sub>DRN</sub> = 5.0 V, T <sub>J</sub> = 125°C	-	14	21	ns
Propagation Delay Time, TG Going High (Nonoverlap Time)	$V_{BST} - V_{DRN} = 5.0 \text{ V}, T_{J} = 125^{\circ}\text{C}$	30	45	60	ns
Propagation Delay Time, TG Going Low	V <sub>BST</sub> – V <sub>DRN</sub> = 5.0 V, T <sub>J</sub> = 125°C	-	18	37	ns
LOW-SIDE DRIVER					
Rise Time	T <sub>J</sub> = 125°C	-	10	15	ns
Fall Time	T <sub>J</sub> = 125°C	-	12	20	ns
Propagation Delay Time, BG Going High (Non-Overlap Time)	T <sub>J</sub> = 125°C	25	55	80	ns
Propagation Delay Time, BG Going Low	T <sub>J</sub> = 125°C	-	10	18	ns
UNDERVOLTAGE LOCKOUT					
V <sub>S</sub> Rising	EN = V <sub>S</sub> , CO = 0 V, dV <sub>S</sub> /dt > 1.0 V/ $\mu$ s, from 4.0 V to 4.5 V, time to BG > 1.0 V, T <sub>J</sub> = 125 °C	-	30	_	μs
V <sub>S</sub> Falling	EN = $V_S$ , CO = 0 V, $dV_S/dt < -1.0 \text{ V/}\mu s$ , from 4.5 V to 4.0 V, time to BG < 1.0 V, $T_{cl}$ = 125°C	-	500	-	μS

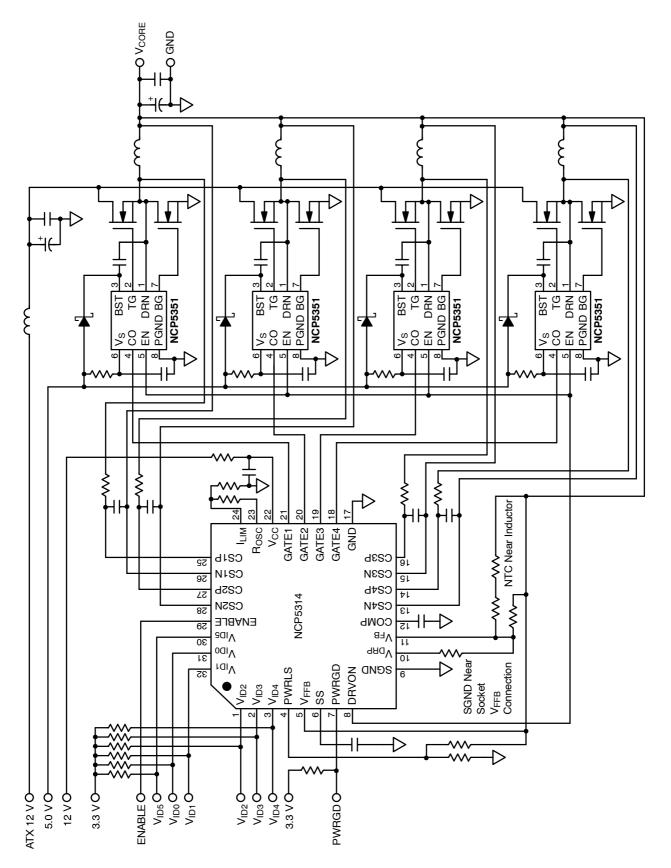


Figure 3. Application Diagram

#### **APPLICATIONS INFORMATION**

# **Theory Of Operation**

#### **Enable Pin**

The Enable Pin (EN) is controlled by a logic level input. With a logic level high on the EN pin, the output states of the drivers are controlled by applying a logic level voltage to the CO pin. With a logic level low both gates are forced low. By bringing both gates low when disabling, the output voltage is prevented from ringing below ground, which could potentially cause damage to the microprocessor or the device being powered.

# **Undervoltage Lockout**

The TG and BG are held low until  $V_S$  reaches 4.25 V during startup. The CO pin takes control of the gates' states when the  $V_S$  threshold is exceeded. If  $V_S$  decreases 300 mV below threshold, the output gate will be forced low and remain low until  $V_S$  rises above startup threshold.

#### **Adaptive Nonoverlap**

The Adaptive Nonoverlap prevents a condition where the top and bottom MOSFETs conduct at the same time and short the input supply. When the top MOSFET is turning off,

the drain (switch node) is sampled and the BG is disabled for a fixed delay time (tpdh $_{\rm BG}$ ) after the drain drops below 4 V, thus eliminating the possibility of shoot–through. When the bottom MOSFET is turning off, TG is disabled for a fixed delay (tpdh $_{\rm TG}$ ) after BG drops below 2.0 V. (See Figure 2 for complete timing information).

# **Layout Guidelines**

When designing any switching regulator, the layout is very important for proper operation. The designer should follow some simple layout guidelines when incorporating gate drivers in their designs. Gate drives experience high di/dt during switching and the inductance of gate drive traces should be minimized. Gate drive traces should be kept as short and wide as practical and should have a return path directly below the gate trace. The use of a ground plane is a desirable way to return ground signals. Also, component location will make a difference. The boost and the V<sub>S</sub> capacitor are the most critical and should be placed as close as possible to the driver IC pins, as shown in Figure 4(a), C21 and C17.

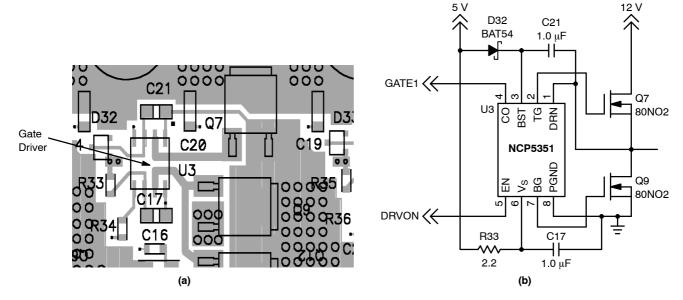


Figure 4. Proper Layout (a), Component Selection (b)

#### TYPICAL PERFORMANCE CHARACTERISTICS

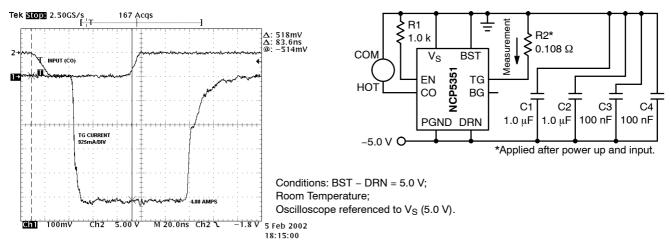


Figure 5. Top Gate Sinking Current from 0.108  $\Omega$ 

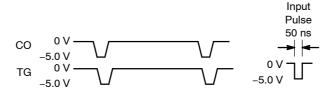


Figure 6. Top Gate Sinking

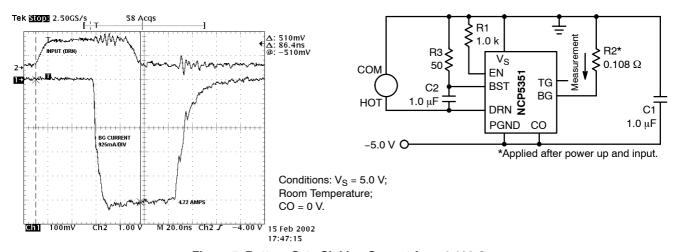


Figure 7. Bottom Gate Sinking Current from 0.108  $\boldsymbol{\Omega}$ 

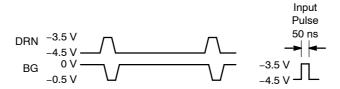


Figure 8. Bottom Gate Sinking

#### TYPICAL PERFORMANCE CHARACTERISTICS

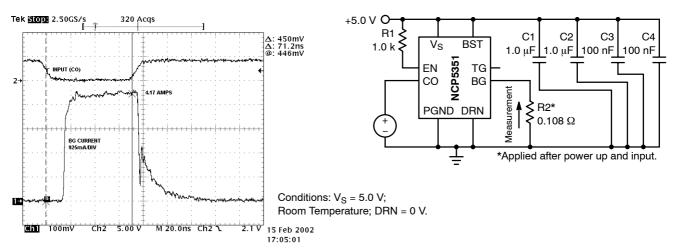


Figure 9. Bottom Gate Sourcing Current into 0.108  $\Omega$ 

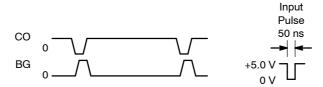


Figure 10. Bottom Gate Sourcing

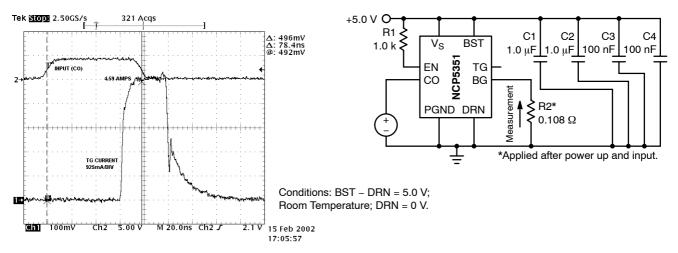


Figure 11. Top Gate Sourcing Current into 0.108  $\Omega$ 

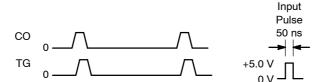


Figure 12. Top Gate Sourcing

# TYPICAL PERFORMANCE CHARACTERISTICS

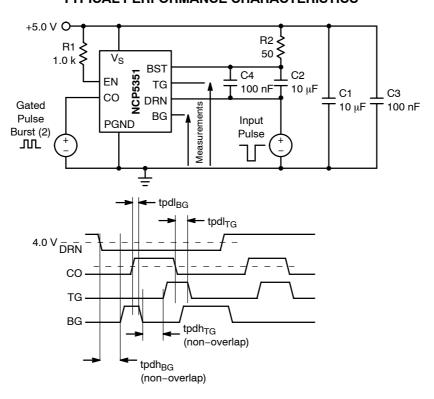
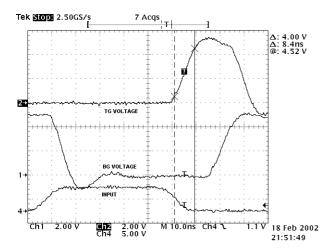
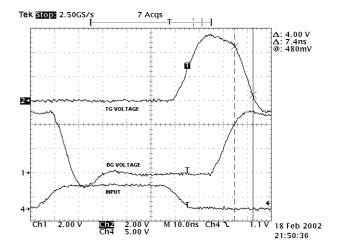


Figure 13. Nonoverlap Test Configuration



Conditions:  $V_S = 5.0 \text{ V}$ ; BST – DRN = 5.0 V;  $C_{LOAD} = 5.7 \text{ nF}$ ; Room Temperature.

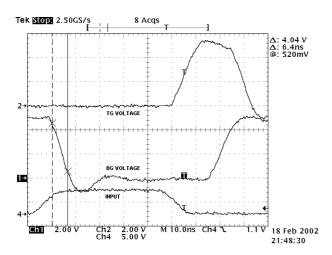
Figure 14. Top Gate Rise Time



Conditions:  $V_S = 5.0 \text{ V}$ ; BST – DRN = 5.0 V;  $C_{LOAD} = 5.7 \text{ nF}$ ; Room Temperature.

Figure 15. Top Gate Fall Time

# TYPICAL PERFORMANCE CHARACTERISTICS



Conditions:  $V_S = 5.0 \text{ V}$ ; BST – DRN = 5.0 V;  $C_{LOAD} = 5.7 \text{ nF}$ ; Room Temperature.

2.50GS/s 245 Acqs
A: 3.96 V
A: 9.6ns
@: 4.48 V

2.00 V Ch2 2.00 V M 10.0ns Ch4 1.1V
18 Feb 2002
21:49:33

Conditions:  $V_S = 5.0 \text{ V}$ ; BST – DRN = 5.0 V;  $C_{LOAD} = 5.7 \text{ nF}$ ; Room Temperature.

Figure 16. Bottom Gate Fall Time

Figure 17. Bottom Gate Rise Time

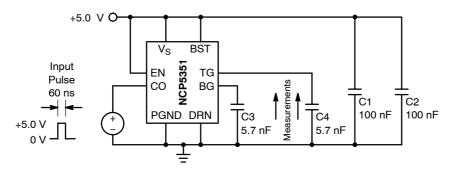
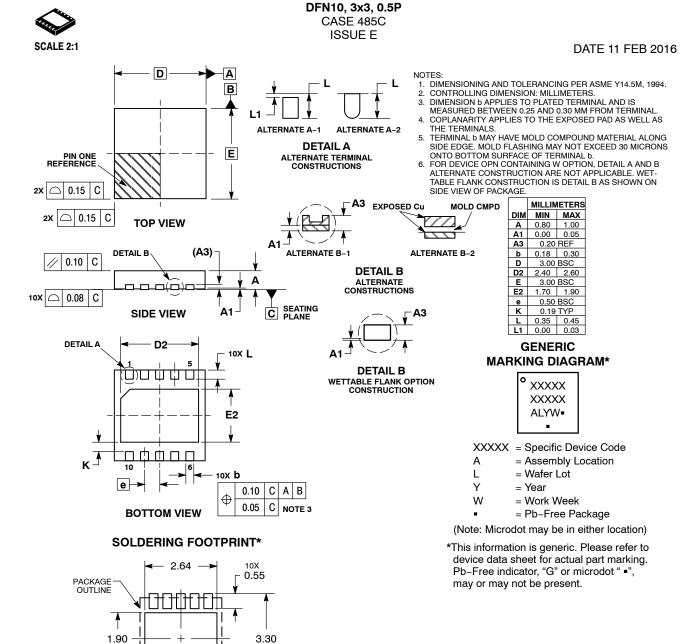


Figure 18. Bottom Gate and Top Gate Rise/Fall Time Test

#### **ORDERING INFORMATION**

Device	Package	Shipping <sup>†</sup>
NCP5351D	SOIC-8	98 Units / Rail
NCP5351DG	SOIC-8 (Pb-Free)	98 Units / Rail
NCP5351DR2	SOIC-8	2500 / Tape & Reel
NCP5351DR2G	SOIC-8 (Pb-Free)	2500 / Tape & Reel
NCP5351MNR2	DFN10	2500 / Tape & Reel
NCP5351MNR2G	DFN10 (Pb-Free)	2500 / Tape & Reel

<sup>†</sup> For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.



*For additional information on our Pb-Free strategy and soldering
details, please download the ON Semiconductor Soldering and
Mounting Techniques Reference Manual, SOLDERRM/D.

10X 0.30

**DIMENSIONS: MILLIMETERS** 

DOCUMENT NUMBER: 98AON03161D

Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.

DESCRIPTION: DFN10, 3X3 MM, 0.5 MM PITCH

PAGE 1 OF 1

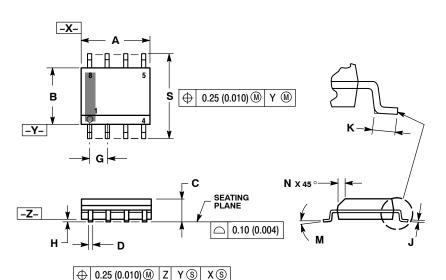
ON Semiconductor and III) are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding

0.50—



SOIC-8 NB CASE 751-07 **ISSUE AK** 

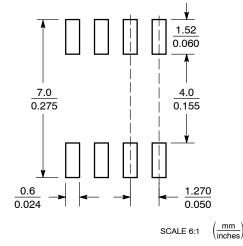
**DATE 16 FEB 2011** 



- NOTES:
  1. DIMENSIONING AND TOLERANCING PER
- ANSI Y14.5M, 1982.
  CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
- 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

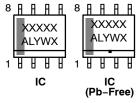
	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
Α	4.80	5.00	0.189	0.197
В	3.80	4.00	0.150	0.157
С	1.35	1.75	0.053	0.069
D	0.33	0.51	0.013	0.020
G	1.27	7 BSC	0.050 BSC	
Н	0.10	0.25	0.004	0.010
7	0.19	0.25	0.007	0.010
K	0.40	1.27	0.016	0.050
M	0 °	8 °	0 °	8 °
N	0.25	0.50	0.010	0.020
S	5.80	6.20	0.228	0.244

# **SOLDERING FOOTPRINT\***



<sup>\*</sup>For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

# **GENERIC MARKING DIAGRAM\***



XXXXX = Specific Device Code = Assembly Location = Wafer Lot = Year = Work Week

= Pb-Free Package

XXXXXX = Specific Device Code = Assembly Location Α = Year ww = Work Week = Pb-Free Package

XXXXXX

AYWW

Discrete

H  $\mathbb{H}$  AYWW

**Discrete** (Pb-Free)

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

# **STYLES ON PAGE 2**

DOCUMENT NUMBER:	98ASB42564B	Electronic versions are uncontrolled except when accessed directly from the Document Rep Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	SOIC-8 NB		PAGE 1 OF 2	

ON Semiconductor and (III) are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the

# SOIC-8 NB CASE 751-07 ISSUE AK

# **DATE 16 FEB 2011**

STYLE 1: PIN 1. EMITTER 2. COLLECTOR 3. COLLECTOR 4. EMITTER 5. EMITTER 6. BASE 7. BASE 8. EMITTER	STYLE 2: PIN 1. COLLECTOR, DIE, #1 2. COLLECTOR, #1 3. COLLECTOR, #2 4. COLLECTOR, #2 5. BASE, #2 6. EMITTER, #2 7. BASE, #1 8. EMITTER, #1	STYLE 3: PIN 1. DRAIN, DIE #1 2. DRAIN, #1 3. DRAIN, #2 4. DRAIN, #2 5. GATE, #2 6. SOURCE, #2 7. GATE, #1 8. SOURCE, #1	STYLE 4: PIN 1. ANODE 2. ANODE 3. ANODE 4. ANODE 5. ANODE 6. ANODE 7. ANODE 8. COMMON CATHODE
STYLE 5: PIN 1. DRAIN 2. DRAIN 3. DRAIN 4. DRAIN 5. GATE 6. GATE 7. SOURCE 8. SOURCE	7. BASE, #1 8. EMITTER, #1  STYLE 6: PIN 1. SOURCE 2. DRAIN 3. DRAIN 4. SOURCE 5. SOURCE 6. GATE 7. GATE 8. SOURCE	STYLE 7: PIN 1. INPUT 2. EXTERNAL BYPASS 3. THIRD STAGE SOURCE 4. GROUND 5. DRAIN 6. GATE 3 7. SECOND STAGE Vd 8. FIRST STAGE Vd	STYLE 8: PIN 1. COLLECTOR, DIE #1 2. BASE, #1 3. BASE, #2
STYLE 9: PIN 1. EMITTER, COMMON 2. COLLECTOR, DIE #1 3. COLLECTOR, DIE #2 4. EMITTER, COMMON 5. EMITTER, COMMON 6. BASE, DIE #2 7. BASE, DIE #1 8. EMITTER, COMMON	STYLE 10: PIN 1. GROUND 2. BIAS 1 3. OUTPUT 4. GROUND 5. GROUND 6. BIAS 2 7. INPUT 8. GROUND	STYLE 11: PIN 1. SOURCE 1 2. GATE 1 3. SOURCE 2 4. GATE 2 5. DRAIN 2 6. DRAIN 2 7. DRAIN 1 8. DRAIN 1	STYLE 12: PIN 1. SOURCE 2. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN
STYLE 13: PIN 1. N.C. 2. SOURCE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN	STYLE 14: PIN 1. N-SOURCE 2. N-GATE 3. P-SOURCE 4. P-GATE 5. P-DRAIN 6. P-DRAIN 7. N-DRAIN 8. N-DRAIN	STYLE 15:  PIN 1. ANODE 1 2. ANODE 1 3. ANODE 1 4. ANODE 1 5. CATHODE, COMMON 6. CATHODE, COMMON 7. CATHODE, COMMON 8. CATHODE, COMMON	STYLE 16:  PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #2 4. BASE, DIE #2 5. COLLECTOR, DIE #2 6. COLLECTOR, DIE #2 7. COLLECTOR, DIE #1 8. COLLECTOR, DIE #1
STYLE 17: PIN 1. VCC 2. V2OUT 3. V1OUT 4. TXE 5. RXE 6. VEE 7. GND 8. ACC	STYLE 18: PIN 1. ANODE 2. ANODE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. CATHODE 8. CATHODE	STYLE 19: PIN 1. SOURCE 1 2. GATE 1 3. SOURCE 2 4. GATE 2 5. DRAIN 2 6. MIRROR 2 7. DRAIN 1 8. MIRROR 1	STYLE 20: PIN 1. SOURCE (N) 2. GATE (N) 3. SOURCE (P) 4. GATE (P) 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN
5. RXE 6. VEE 7. GND 8. ACC STYLE 21: PIN 1. CATHODE 1 2. CATHODE 2 3. CATHODE 3 4. CATHODE 4 5. CATHODE 5 6. COMMON ANODE 7. COMMON ANODE 8. CATHODE 6	STYLE 22: PIN 1. I/O LINE 1 2. COMMON CATHODE/VCC 3. COMMON CATHODE/VCC 4. I/O LINE 3 5. COMMON ANODE/GND 6. I/O LINE 4 7. I/O LINE 5 8. COMMON ANODE/GND	STYLE 23: PIN 1. LINE 1 IN 2. COMMON ANODE/GND 3. COMMON ANODE/GND 4. LINE 2 IN 5. LINE 2 OUT 6. COMMON ANODE/GND 7. COMMON ANODE/GND 8. LINE 1 OUT	STYLE 24: PIN 1. BASE 2. EMITTER 3. COLLECTOR/ANODE 4. COLLECTOR/ANODE 5. CATHODE 6. CATHODE 7. COLLECTOR/ANODE 8. COLLECTOR/ANODE
STYLE 25: PIN 1. VIN 2. N/C 3. REXT 4. GND 5. IOUT 6. IOUT 7. IOUT 8. IOUT	STYLE 26: PIN 1. GND 2. dv/dt 3. ENABLE 4. ILIMIT 5. SOURCE 6. SOURCE 7. SOURCE 8. VCC	STYLE 27: PIN 1. ILIMIT 2. OVLO 3. UVLO 4. INPUT+ 5. SOURCE 6. SOURCE 7. SOURCE 8. DRAIN	STYLE 28: PIN 1. SW_TO_GND 2. DASIC_OFF 3. DASIC_SW_DET 4. GND 5. V_MON 6. VBULK 7. VBULK 8. VIN
STYLE 29: PIN 1. BASE, DIE #1 2. EMITTER, #1 3. BASE, #2 4. EMITTER, #2 5. COLLECTOR, #2 6. COLLECTOR, #2 7. COLLECTOR, #1 8. COLLECTOR, #1	STYLE 30: PIN 1. DRAIN 1 2. DRAIN 1 3. GATE 2 4. SOURCE 2 5. SOURCE 1/DRAIN 2 6. SOURCE 1/DRAIN 2 7. SOURCE 1/DRAIN 2 8. GATE 1		

DOCUMENT NUMBER:	98ASB42564B	Printed versions are uncontrolled except when accessed directly from the Document Repository.  Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.	
DESCRIPTION:	SOIC-8 NB		PAGE 2 OF 2

ON Semiconductor and IN are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.

ON Semiconductor and the are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at <a href="www.onsemi.com/site/pdf/Patent-Marking.pdf">www.onsemi.com/site/pdf/Patent-Marking.pdf</a>. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor and see no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and

# PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:
Email Requests to: orderlit@onsemi.com

ON Semiconductor Website: www.onsemi.com

TECHNICAL SUPPORT
North American Technical Support:
Voice Mail: 1 800-282-9855 Toll Free USA/Canada

Voice Mail: 1800–282–9855 Toll Free USA/Canada
Phone: 011 421 33 790 2910

Phone of the Control of the Control

Europe, Middle East and Africa Technical Support:

Phone: 00421 33 790 2910

For additional information, please contact your local Sales Representative